

## POWER MOS FET FIELD EFFECT POWER TRANSISTOR

IRFD110,111 D82BL2.K2

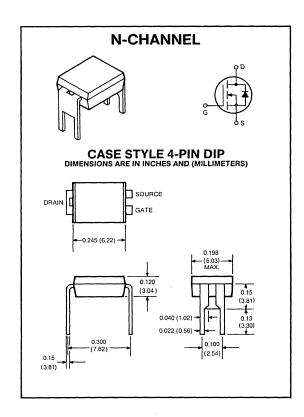
1.0 AMPERES 100, 60 VOLTS RDS(ON) = 0.6  $\Omega$ 

This series of N-Channel Enhancement-mode Power MOSFETs utilizes GE's advanced Power DMOS technology to achieve low on-resistance with excellent device ruggedness and reliability.

This design has been optimized to give superior performance in most switching applications including: switching power supplies, inverters, converters and solenoid/relay drivers. Also, the extended safe operating area with good linear transfer characteristics makes it well suited for many linear applications such as audio amplifiers and servo motors.

## **Features**

- Polysilicon gate Improved stability and reliability
- No secondary breakdown Excellent ruggedness
- Ultra-fast switching Independent of temperature
- Voltage controlled High transconductance
- Low input capacitance Reduced drive requirement
- Excellent thermal stability Ease of paralleling



## maximum ratings $(T_A = 25^{\circ}C)$ (unless otherwise specified)

RATING	SYMBOL	IRFD110/D82BL2	IRFD111/D82BK2	UNITS	
Drain-Source Voltage	V <sub>DSS</sub>	100	60	Volts	
Drain-Gate Voltage, $R_{GS} = 1M\Omega$	V <sub>DGR</sub>	100	60	Volts	
Continuous Drain Current @ $T_A = 25^{\circ}C^{(1)}$ @ $T_A = 100^{\circ}C^{(1)}$	ID	1.0 0.63	1.0 0.63	A A	
Pulsed Drain Current <sup>(2)</sup>	IDM	8.0	8.0	Α	
Gate-Source Voltage	V <sub>GS</sub>	±20	±20	Volts	
Total Power Dissipation @ T <sub>A</sub> = 25°C Derate Above 25°C	P <sub>D</sub>	1.2 9.6	1.2 9.6	Watts mW/°C	
Operating and Storage Junction Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	-55 to 150	°C	

## thermal characteristics

Thermal Resistance, Junction to Ambient <sup>(1)</sup>	$R_{ heta JA}$	105	105	°C/W
Maximum Lead Temperature for Soldering Purposes: 1/8" from Case for 5 Seconds	TL	300	300	°C

<sup>(1)</sup> Device mounted to vertical pc board in free air with drain lead soldered to 0.20 in<sup>2</sup> minimum copper run area.

(2) Repetitive Rating: Pulse width limited by max. junction temperature.

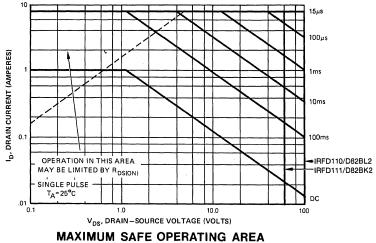
CHARACTERISTIC		SYMBOL	MIN	TYP	MAX	UNIT
off characteristics						
Drain-Source Breakdown Voltage (V <sub>GS</sub> = 0V, I <sub>D</sub> = 250 μA)	IRFD110/D82BL2 IRFD111/D82BK2	BVDSS	100 60	_		Volts
Zero Gate Voltage Drain Current (V <sub>DS</sub> = Max Rating, V <sub>GS</sub> = 0V, T <sub>A</sub> = 25°C) (V <sub>DS</sub> = Max Rating, × 0.8, V <sub>GS</sub> = 0V, T <sub>A</sub> = 125°C)		IDSS			250 1000	μΑ
Gate-Source Leakage Current (V <sub>GS</sub> = ±20V)		I <sub>GSS</sub>			±500	nA
on characteristics*						
Gate Threshold Voltage $T_A = 25^{\circ} C$ $(V_{DS} = V_{GS}, I_D = 250 \mu A)$		V <sub>GS(TH)</sub>	2.0		4.0	Volts
On-State Drain Current (V <sub>GS</sub> = 10V, V <sub>DS</sub> = 10V)		I <sub>D(ON)</sub>	1.0	_		Α
Static Drain-Source On-State Resistance (V <sub>GS</sub> = 10V, I <sub>D</sub> = 0.8A)		R <sub>DS(ON)</sub>	·	0.5	0.6	Ohms
Forward Transconductance (V <sub>DS</sub> = 10V, I <sub>D</sub> = 0.8A)		9fs	0.56	0.75	_	mhos
lynamic characteristic	S					
Input Capacitance	V <sub>GS</sub> = 0V	C <sub>iss</sub>		145	200	pF
Output Capacitance	V <sub>DS</sub> = 25V	Coss		65	100	pF
Reverse Transfer Capacitance	f = 1 MHz	C <sub>rss</sub>		20	25	pF
witching characteristi	cs*					
Turn-on Delay Time	V <sub>DS</sub> = 30V	t <sub>d(on)</sub>		15		ns
Rise Time	I <sub>D</sub> = 0.8A, V <sub>GS</sub> = 15V	t <sub>r</sub>		15	_	ns
Turn-off Delay Time	$R_{GEN} = 50\Omega$ , $R_{GS} = 12.5\Omega$	t <sub>d(off)</sub>		30	_	ns
Fall Time	$(R_{GS (EQUIV.)} = 10\Omega)$	t <sub>f</sub>		10		ns
ource-drain diode rat	ngs and characteri	stics*				
Continuous Source Current		Is			1.0	Α

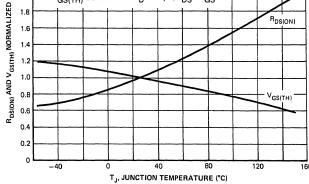
Continuous Source Current	Is			1.0	Α
Pulsed Source Current	I <sub>SM</sub>		_	8.0	Α
Diode Forward Voltage (T <sub>A</sub> = 25°C, V <sub>GS</sub> = 0V, I <sub>S</sub> = 1.0A)	V <sub>SD</sub>	_	0.9	2.5	Volts
Reverse Recovery Time (I <sub>S</sub> = 1.0A, di <sub>S</sub> /dt = 100A/ $\mu$ s, T <sub>A</sub> = 125°C)	t <sub>rr</sub> Q <sub>RR</sub>		90 0.2	_	ns μC

2.2 2.0

1.8

<sup>\*</sup>Pulse Test: Pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%





R<sub>DS(ON)</sub>

 $\begin{array}{c} \textbf{CONDITIONS:} \\ \textbf{R}_{DS(ON)} \text{ CONDITIONS: } \textbf{I}_{D} = 0.8 \text{ A, } \textbf{V}_{GS} = 10 \text{V} \\ \textbf{V}_{GS(TH)} \text{ CONDITIONS: } \textbf{I}_{D} = 250 \mu\text{A, } \textbf{V}_{DS} = \text{V}_{GS} \end{array}$ 

TYPICAL NORMALIZED  $\boldsymbol{R}_{DS[ON]}$  AND  $\boldsymbol{V}_{GS[TH]}\boldsymbol{VS}.$  TEMP.